

<b>Notice of References Cited</b>	Application/Control No. 10/663,742	Applicant(s)/Patent Under Reexamination HAMAMURA ET AL.	
	Examiner Michelle K. Lay	Art Unit 2672	Page 1 of 1

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	B	US-6,868,192 B2	03-2005	Takiguchi, Hideo	382/299
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	M	US-			

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**NON-PATENT DOCUMENTS**

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	U	"IEEE 100 the Authoritative Dictionary of IEEE Standards", 7th edition, Dec. 2000, Institute of Electrical and Electronics Engineers, pp. 104, 306.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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